Automation of Particulate CharacterizationJefferson Lab

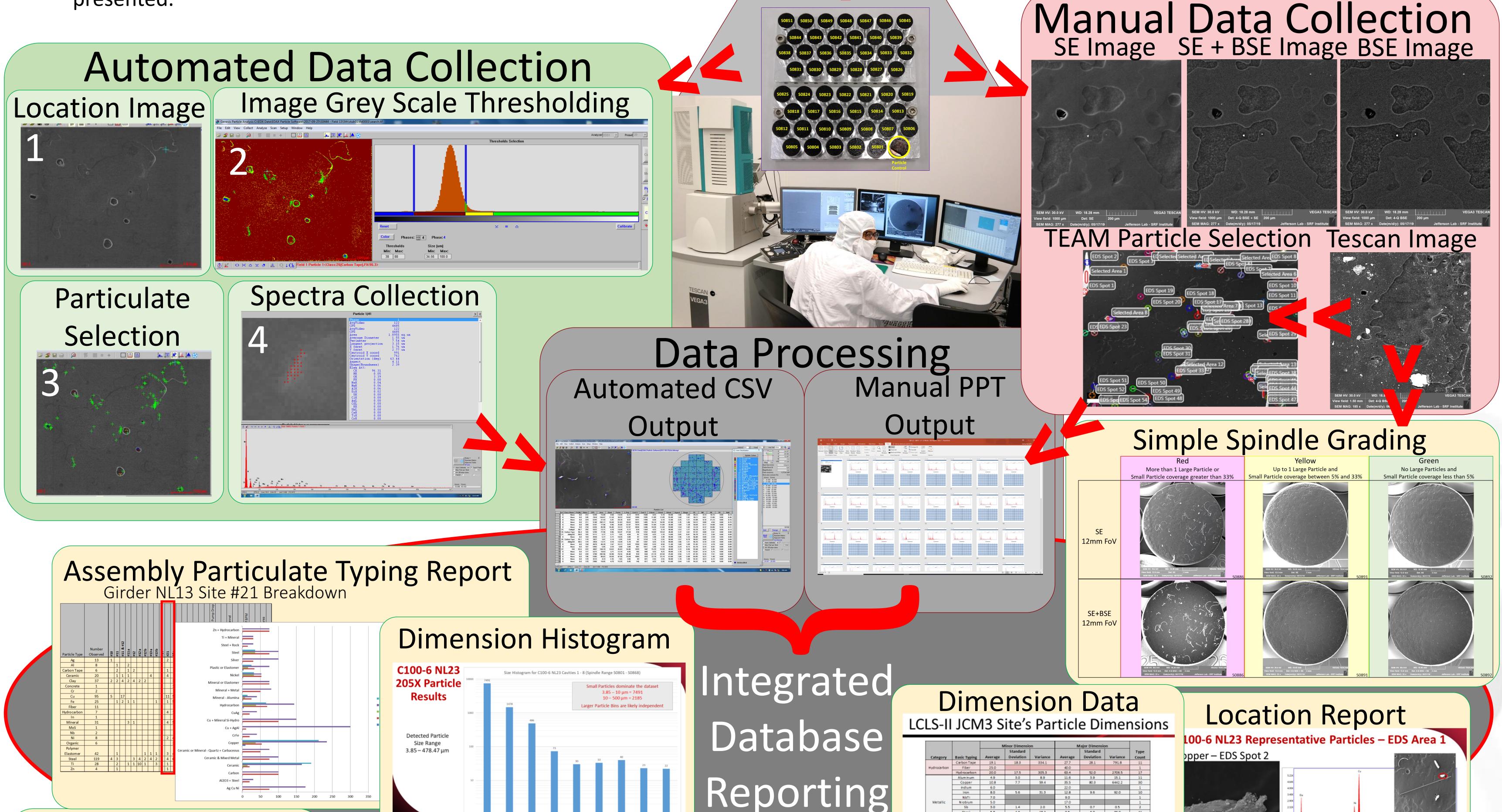
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Abstract

Foreign particulates residing on high electric field surfaces of accelerator cavities present sources for field emission of electrons that limit the useful dynamic range of that cavity. Developing the methods and tools for collecting and characterizing particulates found in an accelerator enables process development towards creating and maintaining field emission free SRF cavities. Methods are presented for sampling assemblies, components, processes, and environmental conditions utilizing forensic techniques with specialized tooling. Sampling activities to date have produced an inventory of over 850 samples. Traditional SEM + EDS analysis of this volume of spindles is challenged by labor investment, spindle sampling methods, and the subsequent data pipeline which ultimately results in a statically inadequate dataset for any particulate distribution characterization. A complete systematic analysis of the spindles is enabled by third party software controlling SEM automation for EDS data acquisition. Details of spindle creation, collection equipment, component sampling, automating particle assessment, and data analysis used to characterize samples from beamline elements in CEBAF are presented.





Summary

Fibers S0828 - Waveguide Bottom C7-17

Findings Report

Waveguide spindles have density fibers than other Waveguide Shaken Contact Swabbing Fibers are likely collected from waveguides. Some fibers from shaken sample show hydrocarbon

Elemental Thresholding

An automated particulate identification system has been developed. This system will target particulate reduction in SRF cavities to reduce field emission.





